

Notice of References Cited	Application/Control No. 10/509,753		Applicant(s)/Patent Under Reexamination YAMAWAKI ET AL.	
	Examiner Junpeng Chen		Art Unit 2631	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,469,105 A	11-1995	Sparks, Geoffrey S.	330/129
*	B	US-5,715,527 A	02-1998	Horii et al.	455/126
*	C	US-2002/0051508 A1	05-2002	Tachimori, Hiroshi	375/376
*	D	US-2002/0090921 A1	07-2002	Midtgaard et al.	455/126
*	E	US-2003/0095608 A1	05-2003	Duperray, David Benoit Didier	375/297
*	F	US-6,636,114 B2	10-2003	Tsutsui et al.	330/51
*	G	US-6,671,337 B1	12-2003	Cordoba, Jose Luis	375/345
*	H	US-6,766,156 B1	07-2004	Hayashihara, Mikio	455/295
*	I	US-6,801,784 B1	10-2004	Rozenblit et al.	455/522
*	J	US-6,853,836 B2	02-2005	Asam et al.	455/126
*	K	US-2005/0218989 A1	10-2005	Tsutsui et al.	330/285
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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